

## SUPPLEMENTARY INFORMATION

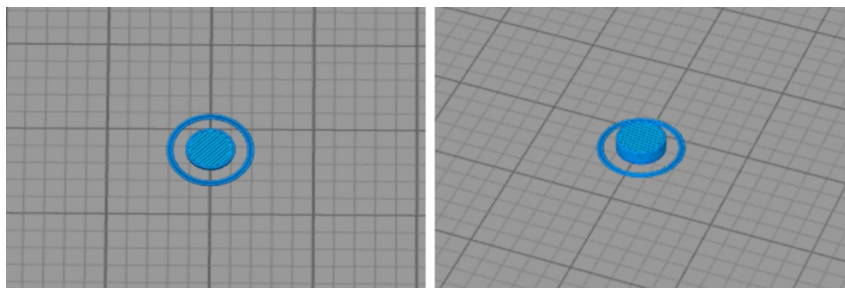


Figure S1. Simplify3D Professional software images of the printed PLA:CaP:GO scaffold model from different perspectives and at different times of the printing process.

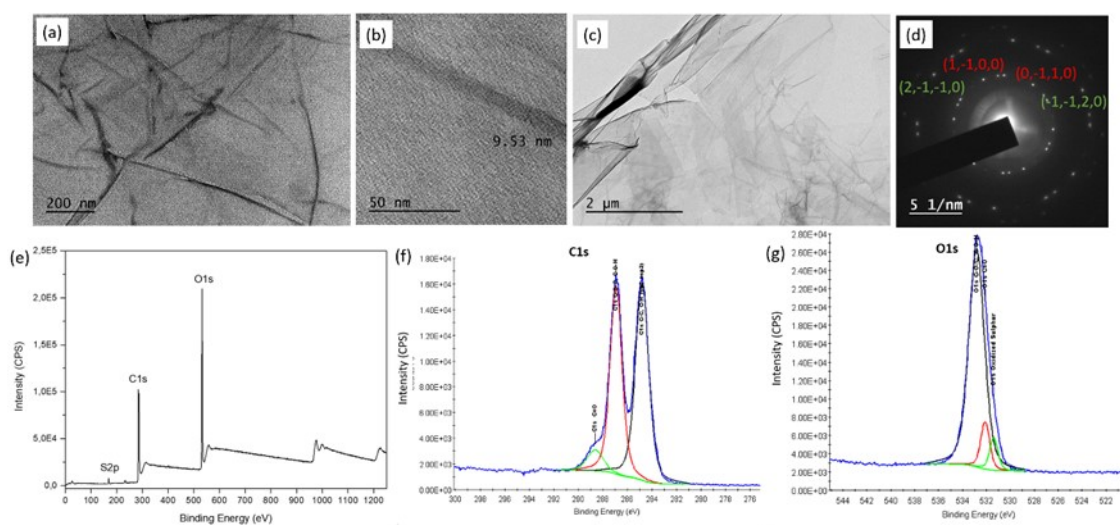


Figure S2. TEM micrographs of GO sheets (a-d) in general appearance (a), thickness measurement of the sheet folds  $\pm 0.01$  nm (b), extended sheet at 4000x (c) and inverted SAED pattern (d). XPS analysis (e-g) with general spectrum of GO sheets (e) and high-resolution spectra for the electronic transitions of C1s (f) and O1s (g).

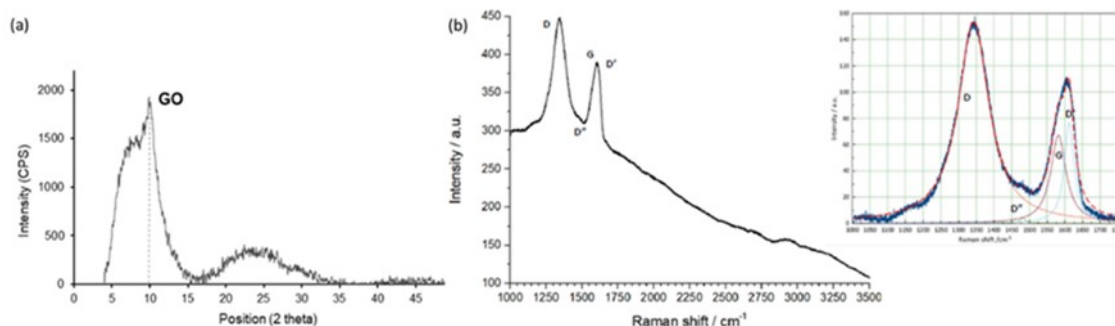


Figure S3. XRD diffraction pattern (a) and FT-Raman spectrum of GO sheets, with the corresponding deconvolution.